Ferroelectricity Driven by Twisting of Silicate Tetrahedral Chains

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To date, ferroelectric materials have been widely applied in various electronic devices, including actuators, non-volatile memory, and sensors. Ferroelectric materials traditionally comprise oxygen octahedral units, such as those found in perovskite-type oxides. The strong covalency of the cations in the perovskite structures plays an important role for achieving robust ferroelectricity with a high- T_c and a large spontaneous polarization. With this in mind, recent ferroelectric devices typically rely on the use of lead-based compounds such as Pb(Zr,Ti)O₃ (PZT) to achieve such robust ferroelectricity. Mindful of the toxicity of Pb, there is an increasing demand for sustainable and environmentally friendly electronic devices, free from toxic elements. As such, a new guiding principle for designing ferroelectric materials is necessary.

In the present study, we demonstrate the occurrence of ferroelectricity in a silicatebased compound, Bi₂SiO₅, by direct observation of polarization switching. The novel mechanism of ferroelectricity in Bi₂SiO₅ has been elucidated from comprehensive studies employing Raman scattering, transmission electron microscopy, X-ray powder diffraction, and first principles calculations. The obtained experimental results and calculations clarified that the observed ferroelectricity in Bi₂SiO₅ stems from twisting of the one-dimensional SiO₄ tetrahedral chain.[1] This recent discovery opens up a new frontier for designing functional oxides based on "tetrahedra-engineering", as opposed to conventional "octahedraengineering". Furthermore, it also provides a guiding principle for the development of sustainable and environmentally friendly electronic and electro-mechanical devices, as compounds comprising tetrahedral chains are widely found in rock-forming oxides, which are abundant in the earth's crust.

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Reference:

[1] H. Taniguchi et al., Angew. Chem. Int. Ed. 52 (2013) 1-6.